

Appl. No.: 10/626,903

Amdt. dated: August 1, 2005

Reply to Office action of 05/24/2005

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

1 (currently amended): An enclosure for a probe station chuck, said probe station chuck including a device supporting surface and a thermal device arranged to modify a temperature of said device supporting surface, said enclosure comprising a conductive wall including an inner surface, said inner surface having a portion separating said device supporting surface from said thermal device and defining a chamber substantially enclosing said device supporting surface and having a portion separating said device supporting surface from said thermal device.

2 (original): The enclosure of claim 1 further comprising an electrically conductive connection of said conductive wall to an instrument.

3 (original): The enclosure of claim 2 further comprising an electrically conductive connection of said instrument to a ground.

4 (original): The enclosure of claim 1 further comprising:

- (a) an electrically conductive connection of said conductive wall to an instrument; and
- (b) a switch having a first terminal selectively connectable to a second terminal, said second terminal being conductively connected to said conductive wall and said first terminal being conductively connected to a ground.

5 (original): The enclosure of claim 4 further comprising an electrically conductive connection of said instrument to a ground.

6 (original): The enclosure of claim 1 wherein said conductive wall further comprises a portion separating said device supporting surface from an electrical conductor arranged to conduct electrical energy from a controller to said thermal device.

Appl. No.: 10/626,903

Amdt. dated: August 1, 2005

Reply to Office action of 05/24/2005

7 (original): The enclosure of claim 6 further comprising an electrically conductive connection of said conductive wall to an instrument.

8 (original): The enclosure of claim 7 further comprising an electrically conductive connection of said instrument to a ground.

9 (original): The enclosure of claim 6 further comprising:

- (a) an electrically conductive connection of said conductive wall to an instrument; and
- (b) a switch having a first terminal selectively connectable to a second terminal, said second terminal being conductively connected to said conductive wall and said first terminal being conductively connected to a ground.

10 (original): The enclosure of claim 9 further comprising an electrically conductive connection of said instrument to a ground.

11 (currently amended): An enclosure for a probe station chuck, said probe station chuck including a device supporting surface and a thermal device arranged to modify a temperature of said device supporting surface, said enclosure comprising a conductive wall including

- (a) an inner surface, said inner surface having a portion separating said device supporting surface from said thermal device and defining a chamber substantially enclosing said device supporting surface and having a portion separating said device supporting surface from said thermal device; and
- (b) an outer surface, said outer surface including a portion substantially encircling a portion of said thermal device.

Appl. No.: 10/626,903
Amdt. dated: August 1, 2005
Reply to Office action of 05/24/2005

12 (original): The enclosure of claim 11 further comprising an electrically conductive connection of said conductive wall to an instrument.

13 (original): The enclosure of claim 12 further comprising an electrically conductive connection of said instrument to a ground.

14 (original): The enclosure of claim 11 further comprising:

- (a) an electrically conductive connection of said conductive wall to an instrument; and
- (b) a switch having a first terminal selectively connectable to a second terminal, said second terminal being conductively connected to said conductive wall and said first terminal being conductively connected to a ground.

15 (original): The enclosure of claim 14 further comprising an electrically conductive connection of said instrument to a ground.

16 (original): The enclosure of claim 11 wherein said outer surface includes another portion substantially encircling a portion of an electrical conductor arranged to conduct electrical energy from a controller to said thermal device.

17 (original): The enclosure of claim 16 further comprising an electrically conductive connection of said conductive wall to an instrument.

18 (original): The enclosure of claim 17 further comprising an electrically conductive connection of said instrument to a ground.

Appl. No.: 10/626,903
Amdt. dated: August 1, 2005
Reply to Office action of 05/24/2005

19 (original): The enclosure of claim 16 further comprising:

- (a) an electrically conductive connection of said conductive wall to an instrument;
and
- (b) a switch having a first terminal selectively connectable to a second terminal,
said second terminal being conductively connected to said conductive wall
and said first terminal being conductively connected to a ground.

20 (original): The enclosure of claim 19 further comprising an electrically conductive
connection of said instrument to a ground.